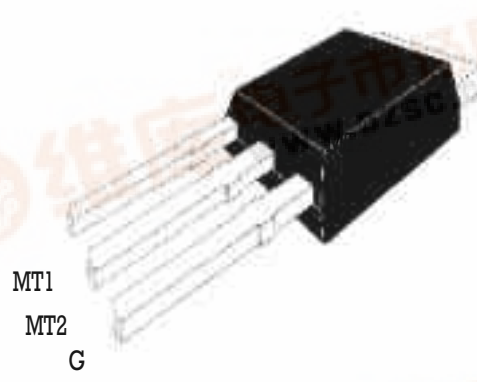




FT04...I

LOGIC LEVEL TRIAC

**IPAK
(Plastic)**



MT1
MT2
G

On-State Current **Gate Trigger Current**
4 Amp < 5 mA to < 10 mA

Off-State Voltage
200 V ÷ 600 V

This series of **TRIACs** uses a high performance PNP technology.

These parts are intended for general purpose applications where logic compatible gate sensitivity is required, like touch dimmers, fan, electrovalve control.

Absolute Maximum Ratings, according to IEC publication No. 134

SYMBOL	PARAMETER	CONDITIONS	Min.	Max.	Unit
$I_{T(RMS)}$	RMS On-state Current	All Conduction Angle, $T_c = 110\text{ }^\circ\text{C}$	4		A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 60 Hz	31		A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 50 Hz	30		A
I^2t	Fusing Current	$t_p = 10\text{ ms}$, Half Cycle	5.1		A ² s
I_{GM}	Peak Gate Current	20 μs max.		4	A
P_{GM}	Peak Gate Dissipation	20 μs max.		3	W
$P_{G(AV)}$	Gate Dissipation	20 ms max.		1	W
di/dt	Critical rate of rise of on-state current	$I_G = 2 \times I_{CT}$ Tr 100 ns, F = 120 Hz $T_j = 125\text{ }^\circ\text{C}$	50		A/ μs
T_j	Operating Temperature		-40	+125	$^\circ\text{C}$
T_{stg}	Storage Temperature		-40	+150	$^\circ\text{C}$
T_{sld}	Soldering Temperature	4.5 mm from case, 10s max.		260	$^\circ\text{C}$

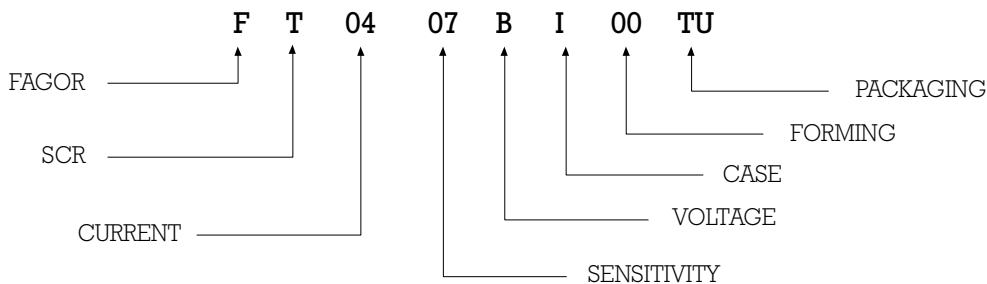
SYMBOL	PARAMETER	VOLTAGE			Unit
		B	D	M	
V_{DRM} V_{RRM}	Repetitive Peak Off State Voltage	200	400	600	V



LOGIC LEVEL TRIAC
Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	Quadrant		SENSITIVITY		Unit
					07	08	
I_{GT}	Gate Trigger Current	$V_D = 12 V_{DC}, R_L = 30 \Omega, T_j = 25^\circ C$	Q1÷Q3 Q4	MAX MAX	5 7	10	mA
I_{DRM} / I_{RRM}	Off-State Leakage Current	$V_D = V_{DRM}, T_j = 125^\circ C$ $V_R = V_{RRM}, T_j = 25^\circ C$		MAX MAX	1 5		mA μA
V_{to}	Threshold Voltage	$T_j = 125^\circ C$		MAX	0.9		V
R_d	Dynamic Resistance	$T_j = 125^\circ C$		MAX	120		m
V_{TM}^*	On-state Voltage	$I_T = 5.5 \text{ Amp}, t_p = 380 \mu s, T_j = 25^\circ C$		MAX	1.6		V
V_{GT}	Gate Trigger Voltage	$V_D = 12 V_{DC}, R_L = 30 \Omega, T_j = 25^\circ C$	Q1÷Q3	MAX	1.3		V
V_{GD}	Gate Non Trigger Voltage	$V_D = V_{DRM}, R_L = 3.3K \Omega, T_j = 125^\circ C$	Q1÷Q3	MIN	0.2		V
I_H^*	Holding Current	$I_T = 100 \text{ mA}, \text{ Gate Open}, T_j = 25^\circ C$		MAX	10	15	mA
I_L	Latching Current	$I_G = 1.2 I_{GT}, T_j = 25^\circ C$	Q1,Q3,Q4 Q2	MAX MAX	10 15	20 30	mA
dv / dt^*	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}, \text{ Gate open}$ $T_j = 125^\circ C$		MIN	20	100	V/ μs
$R_{th(j-c)}$	Thermal Resistance Junction-Case for AC				2.6		$^\circ C/W$
$R_{th(j-a)}$	Thermal Resistance Junction-Ambient				100		$^\circ C/W$

(*) For either polarity of electrode MT2 voltage with reference to electrode MT1.

PART NUMBER INFORMATION


LOGIC LEVEL TRIAC

Fig. 1: Maximum RMS power dissipation versus RMS on-state current.

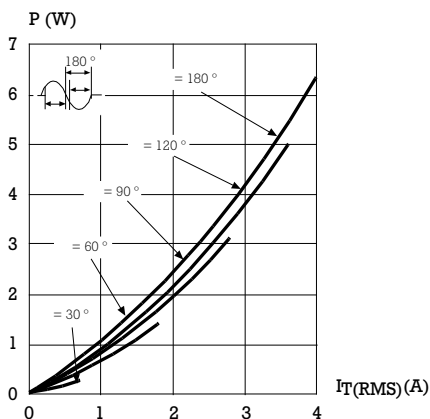


Fig. 3: RMS on-state current versus case temperature.

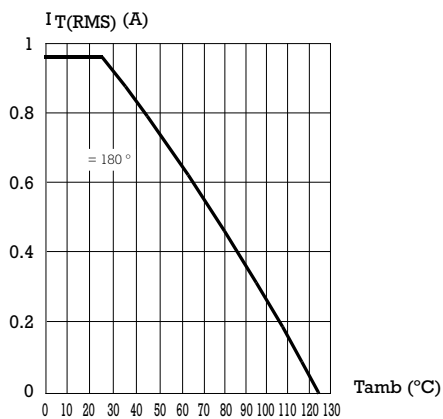


Fig. 5: Relative variation of gate trigger current and holding current versus junction temperature.

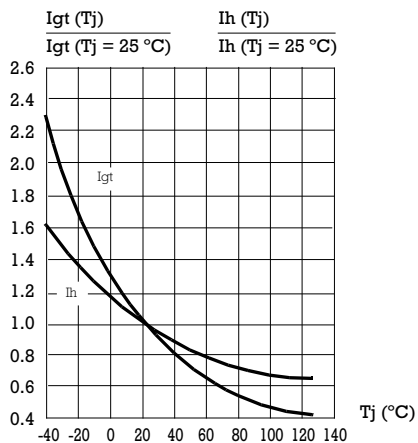


Fig. 2: Correlation between maximum RMS power dissipation and maximum allowable temperature (Tamb and T case).

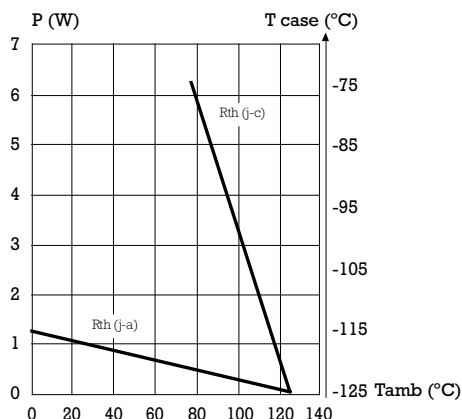


Fig. 4: Relative variation of thermal impedance junction to ambient versus pulse duration.

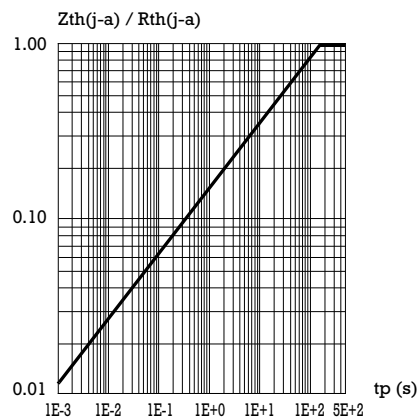
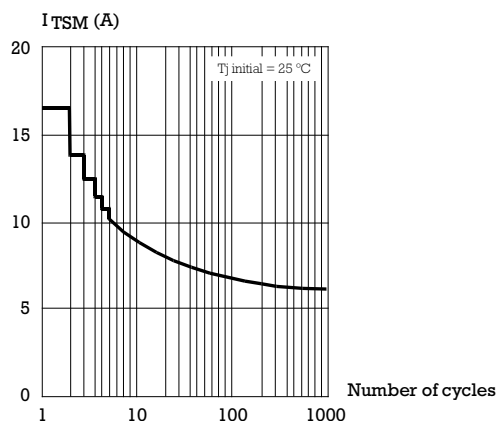


Fig. 6: Non repetitive surge peak on-state current versus number of cycles.



LOGIC LEVEL TRIAC

Fig. 7: Non repetitive surge peak on-state current for a sinusoidal pulse with width: t_p 10 ms, and corresponding value of I^2t .

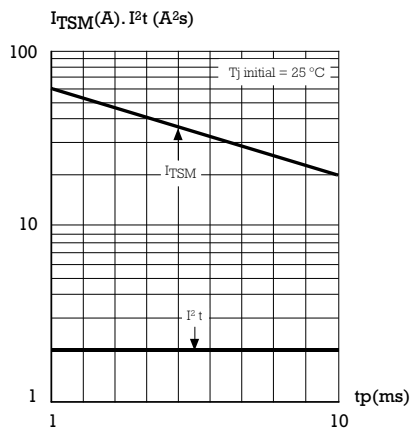
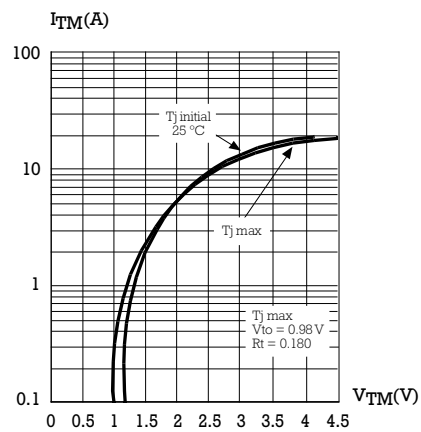
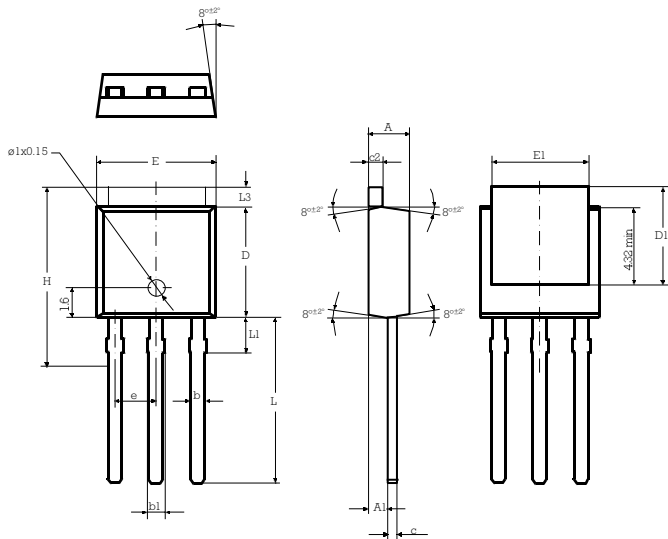


Fig. 8: On-state characteristics (maximum values).



PACKAGE MECHANICAL DATA IPAK TO 251-AA



REF.	DIMENSIONS		
	Milimeters		
	Min.	Nominal	Max.
A	2.19	2.3±0.08	2.38
A1	0.89	1.067±0.01	1.14
b	0.64	0.75±0.1	0.89
b1	0.76	0.95	1.14
c	0.46		0.58
c2		0.8±0.013	
D	5.97	6.1±0.1	6.22
D1	5.21		5.52
E	6.35	6.58±0.14	6.73
E1	5.21	5.36±0.1	5.46
e		2.28BSC	
L	8.89	9.2±0.2	9.65
L1	1.91	2±0.1	2.28
L3	0.89		1.27

Marking: type number
Weight: 0.2 g